

**Product Summary**

$V_{DS}$	1200 V
$I_D (T_C=25^\circ\text{C})$	73 A
$R_{DS(on),typ}$	40 m $\Omega$ @ $V_{GS}=18\text{V}$

**Features**

- Low On-Resistance with High Blocking Voltage
- Low Capacitance
- Avalanche Ruggedness
- Halogen Free, Rohs Compliant
- AEC-Q101 Qualified and PPAP Capable

**Benefits**

- High Frequency Operation
- Enabling Higher Switching Frequency
- Increased Power Density
- Reduction of Heat Sink Requirements

**Applications**

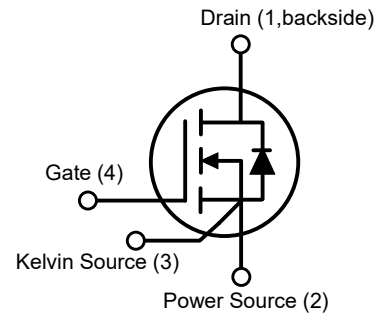
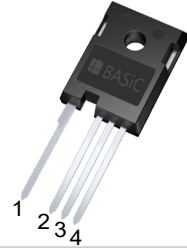
- On Board Charger(OBC)
- DC/DC Converter for EV/HEV
- Automotive Air-Conditioning Compressor
- Auxiliary drives

**Package Pin Definitions**

- Pin1 and backside - Drain
- Pin2 - Power Source
- Pin3 - Kelvin Source
- Pin4 - Gate

**Package Parameters**

Part Number	Marking	Package
AB2M040120Z	AB2M040120Z	TO-247-4

**Package: TO-247-4**


**Maximum Ratings**

Symbol	Parameter	Test conditions	Value	Unit
$V_{DSmax}$	Drain-Source Voltage	$V_{GS}=0V, I_D=100\mu A$	1200	V
$V_{GSmax}^{1)}$	Gate-Source Voltage		-10/22	V
$V_{GSop}$	Recommend Gate-Source Voltage		-4/18	V
$I_D$	Continuous Drain Current	$V_{GS}=18V, T_C=25^\circ C$	73	A
		$V_{GS}=18V, T_C=100^\circ C$	51	A
$I_{D,pulse}$	Pulsed Drain Current	Pulse with $t_p$ limited by $T_{jmax}$	128	A
$P_{tot}$	Power Dissipation	$T_C=25^\circ C, T_j=175^\circ C$	348	W
$E_{AS}$	Single pulse avalanche energy	$T_C=25^\circ C, L=2mH, I_{AS}=20A, V_{DD}=140V$	400	mJ
$T_j$	Operating Junction Temperature		-55~175	$^\circ C$
$T_{stg}$	Storage Temperature		-55~175	$^\circ C$
$M_d$	TO-247 mounting torque	M3 Screw	0.7	N·m

1) Note: When using MOSFET Body Diode  $V_{GSmax}=-4/22V$

**Electrical Characteristics (Defined at  $T_j=25^\circ C$  unless otherwise specified)**  
**Static Characteristics**

Symbol	Parameter	Test conditions	Value			Unit
			Min.	Typ.	Max.	
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=100\mu A$	1200			V
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=10mA$	2.3	2.7	3.5	V
		$V_{GS}=V_{DS}, I_D=10mA, T_j=175^\circ C$		1.9		
$I_{GSS}$	Gate-Source Leakage Current	$V_{GS}=18V, V_{DS}=0V$			100	nA
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=1200V, V_{GS}=0V$		1	50	$\mu A$
		$V_{DS}=1200V, V_{GS}=0V, T_j=175^\circ C$		10	200	
$R_{DS(on)}$	Drain-Source On-State Resistance	$V_{GS}=18V, I_D=40A$		40	55	m $\Omega$
		$V_{GS}=18V, I_D=40A, T_j=175^\circ C$		65		
		$V_{GS}=15V, I_D=40A$		50		
$g_{fs}$	Transconductance	$V_{DS}=10V, I_D=40A$		16		S

**Thermal Characteristics**

Symbol	Parameter	Value			Unit
		Min.	Typ.	Max.	
$R_{th(jc)}$	Thermal Resistance from Junction to Case		0.43	0.60	K/W

**AC Characteristics**

Symbol	Parameter	Test conditions	Value			Unit
			Min.	Typ.	Max.	
$C_{iss}$	Input Capacitance	$V_{GS}=0V, V_{DS}=800V$ $f=100kHz, V_{AC}=25mV$		2100		pF
$C_{oss}$	Output Capacitance			115		pF
$C_{rss}$	Reverse Transfer Capacitance			6		pF
$E_{oss}$	$C_{oss}$ Stored Energy			47		μJ
$C_{O(ER)}$	Effective Output Capacitance, Energy Related	$V_{GS}=0V, 0V < V_{DS} < 800V$		147		pF
$C_{O(TR)}$	Effective Output Capacitance, Time Related	$V_{GS}=0V, 0V < V_{DS} < 800V$		215		pF
$R_{G(int)}$	Internal Gate Resistance	$f=1MHz, V_{AC}=25mV$		1.6		Ω

**Gate Charge Characteristics**

Symbol	Parameter	Test conditions	Value			Unit
			Min.	Typ.	Max.	
$Q_{GS}$	Gate to Source Charge	$V_{DS}=800V$ $I_D=40A$ $V_{GS}=-4/+18V$		30		nC
$Q_{GD}$	Gate to Drain Charge			42		nC
$Q_G$	Total Gate Charge			90		nC

**Switching Characteristics**

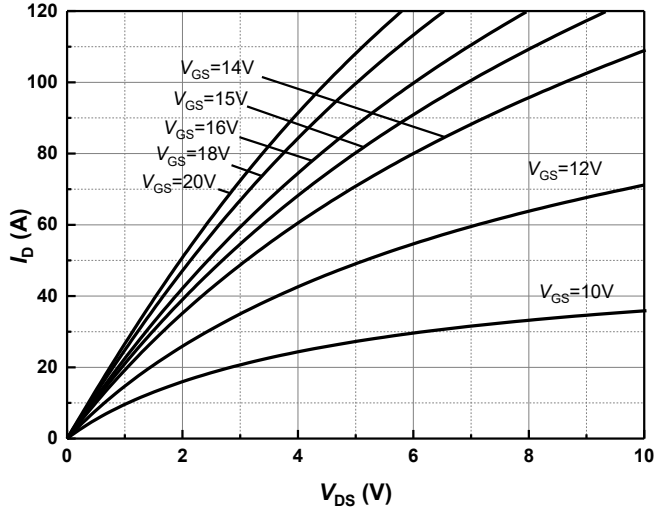
Symbol	Parameter	Test conditions	Value			Unit
			Min.	Typ.	Max.	
$t_{d(on)}$	Turn-On Delay Time			31		ns
$t_r$	Rise Time	$V_{DC}=800V, V_{GS}=-4/18V$ $I_D=40A, R_{G(ext)}=8.2\Omega$		20		ns
$t_{d(off)}$	Turn-Off Delay Time	$L_\sigma=60nH, T_j=25^\circ C$ FWD <sup>2)</sup> : body diode at $V_{GS}=-4V$		30		ns
$t_f$	Fall Time	Inductive Load Eon includes diode reverse recovery		14		ns
$E_{on}$	Turn-On Energy (Body Diode FWD)			800		uJ
$E_{off}$	Turn-Off Energy (Body Diode FWD)			280		uJ
$E_{on}$	Turn-On Energy (SiC Diode FWD)	$V_{DC}=800V, V_{GS}=-4/18V$ $I_D=40A, R_{G(ext)}=8.2\Omega$		720		uJ
$E_{off}$	Turn-Off Energy (SiC Diode FWD)	$L_\sigma=60nH, T_j=25^\circ C$ FWD <sup>2)</sup> : B2D40120H1		240		uJ
$t_{d(on)}$	Turn-On Delay Time			30		ns
$t_r$	Rise Time	$V_{DC}=800V, V_{GS}=-4/18V$ $I_D=40A, R_{G(ext)}=8.2\Omega$		17		ns
$t_{d(off)}$	Turn-Off Delay Time	$L_\sigma=60nH, T_j=175^\circ C$ FWD <sup>2)</sup> : body diode at $V_{GS}=-4V$		35		ns
$t_f$	Fall Time	Inductive Load Eon includes diode reverse recovery		14		ns
$E_{on}$	Turn-On Energy (Body Diode FWD)			1090		uJ
$E_{off}$	Turn-Off Energy (Body Diode FWD)			260		uJ
$E_{on}$	Turn-On Energy (SiC Diode FWD)	$V_{DC}=800V, V_{GS}=-4/18V$ $I_D=40A, R_{G(ext)}=8.2\Omega$		580		uJ
$E_{off}$	Turn-Off Energy (SiC Diode FWD)	$L_\sigma=60nH, T_j=175^\circ C$ FWD <sup>2)</sup> : B2D40120H1		230		uJ

2) Note: FWD: Freewheeling diode

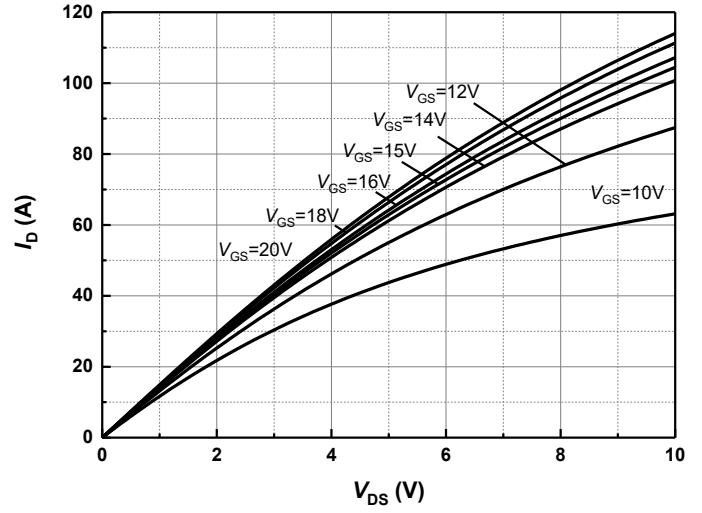
**Reverse Diode Characteristics**

Symbol	Parameter	Test conditions	Value			Unit
			Min.	Typ.	Max.	
$V_{SD}$	Diode Forward Voltage	$V_{GS}=-4V, I_{SD}=20A, T_j=25^{\circ}C$		4.6		V
		$V_{GS}=-4V, I_{SD}=20A, T_j=175^{\circ}C$		4.0		
$I_{SD}$	Continuous Diode Forward Current	$V_{GS}=-4V, T_c=25^{\circ}C$			52	A
$I_{SD,pulse}$	Pulse Diode Current	$V_{GS}=-4V$ , pulse width $t_p$ limited by $T_{jmax}$		129		A
$t_{rr}$	Reverse Recovery Time	$V_{DC}=800V, I_{SD}=40A$ $-di_F/dt=2400A/\mu s$ $T_j=25^{\circ}C$		21		ns
$Q_{rr}$	Reverse Recovery Charge			200		nC
$I_{rrm}$	Peak Reverse Recovery Current			17		A
$t_{rr}$	Reverse Recovery Time	$V_{DC}=800V, I_{SD}=40A$ $-di_F/dt=2800A/\mu s$ $T_j=175^{\circ}C$		32		ns
$Q_{rr}$	Reverse Recovery Charge			840		nC
$I_{rrm}$	Peak Reverse Recovery Current			50		A

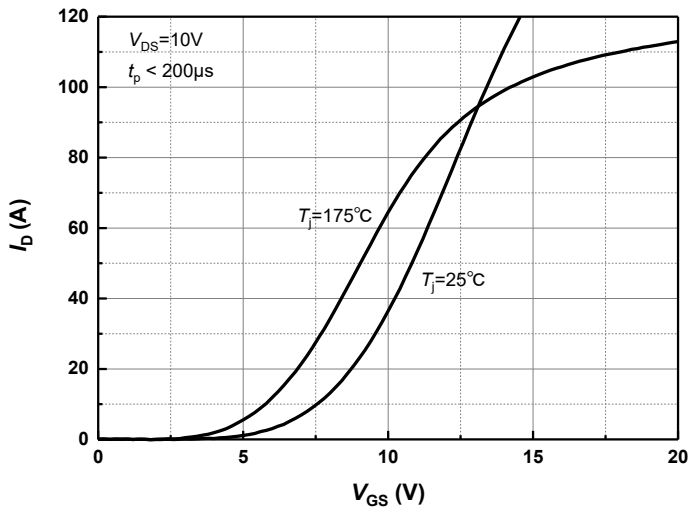
**Typical Performance**



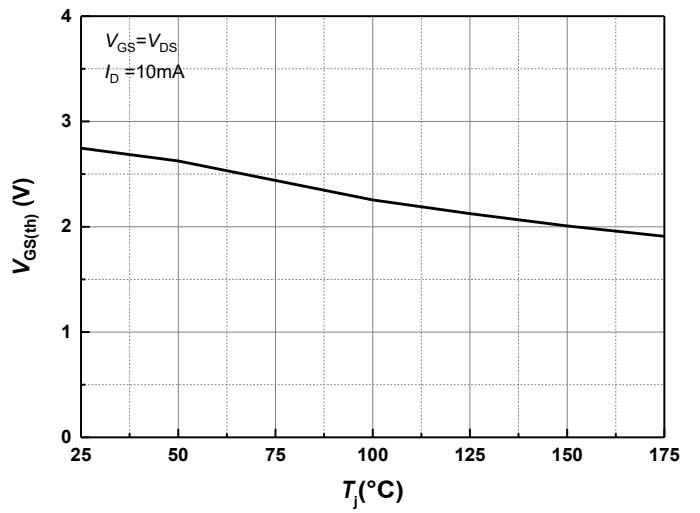
**Figure 1** Typical Forward Output Characteristics at  $T_j = 25^\circ\text{C}$



**Figure 2** Typical Forward Output Characteristics at  $T_j = 175^\circ\text{C}$

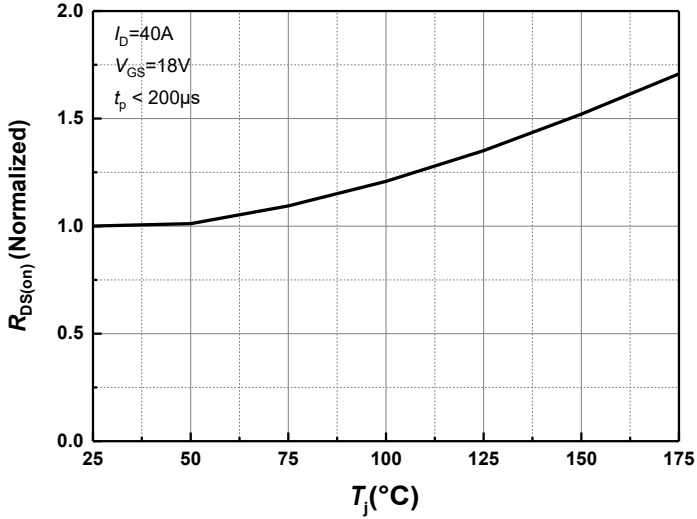


**Figure 3** Transfer Characteristics for Various Temperature

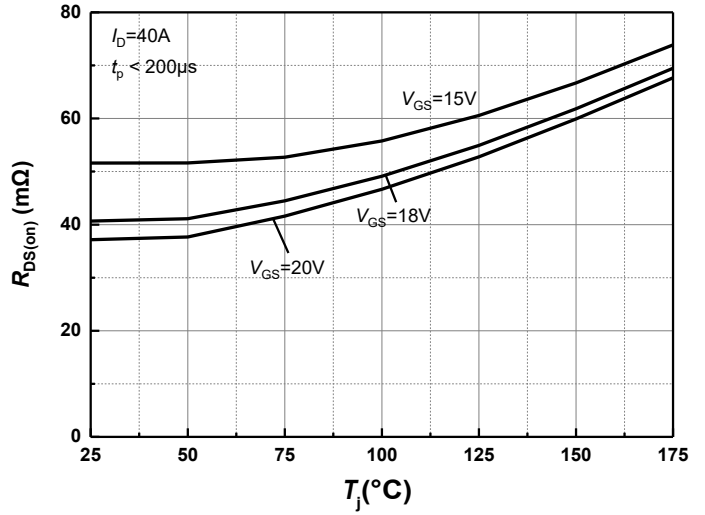


**Figure 4** Threshold Voltage for Various Temperature

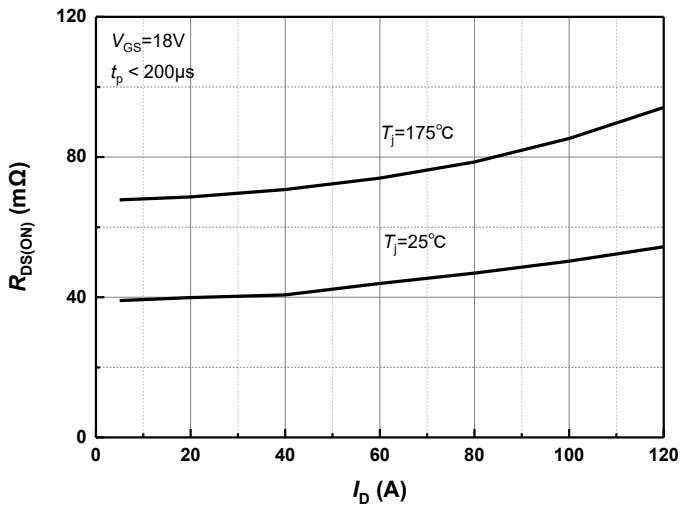
**Typical Performance**



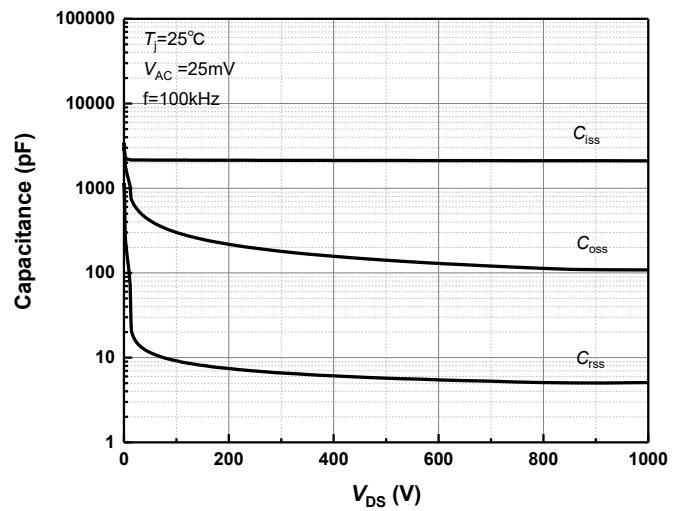
**Figure 5** Normalized On-Resistance for Various Temperature



**Figure 6** On-Resistance vs. Temperature for Various Gate-Source Voltage

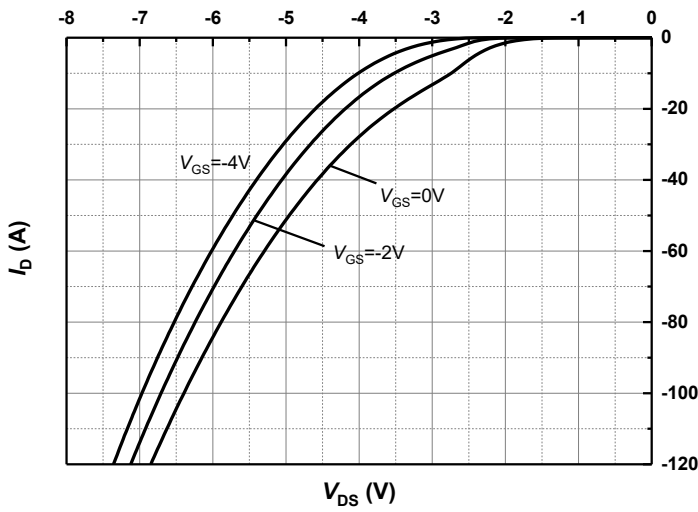


**Figure 7** On-Resistance vs. Drain Current for Various Temperature

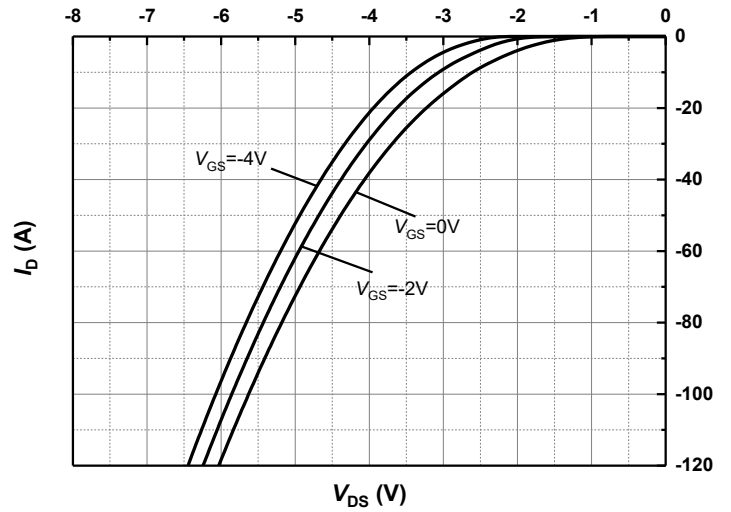


**Figure 8** Capacitance vs. Drain-Source Voltage (0 - 1000V)

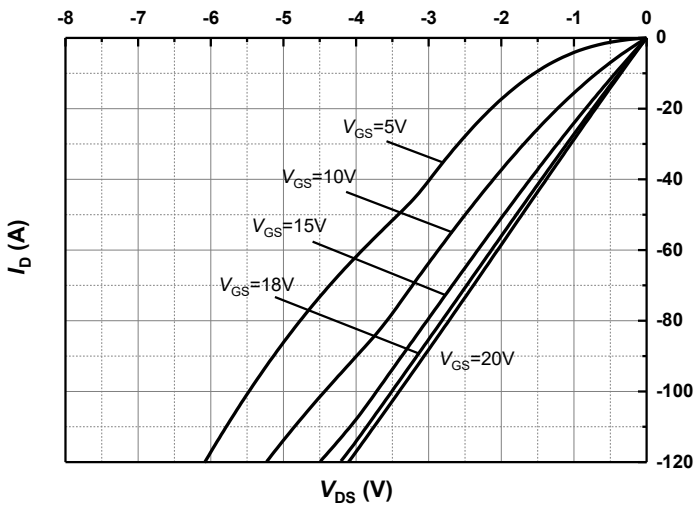
**Typical Performance**



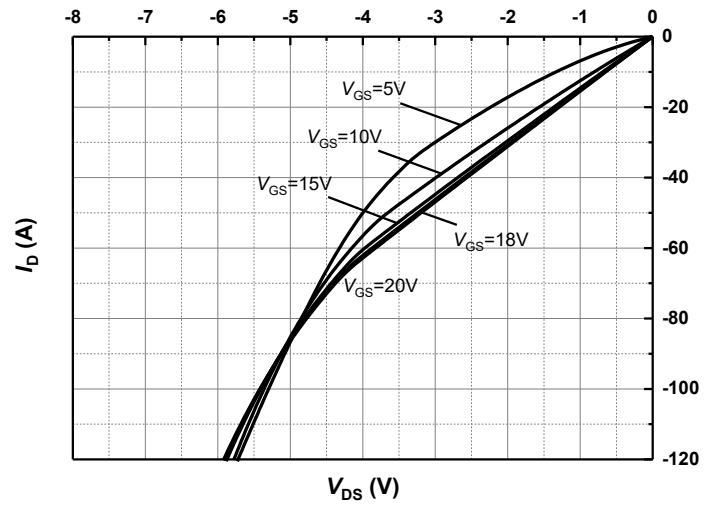
**Figure 9** Body Diode Characteristics at  $T_j=25^\circ\text{C}$



**Figure 10** Body Diode Characteristics at  $T_j=175^\circ\text{C}$

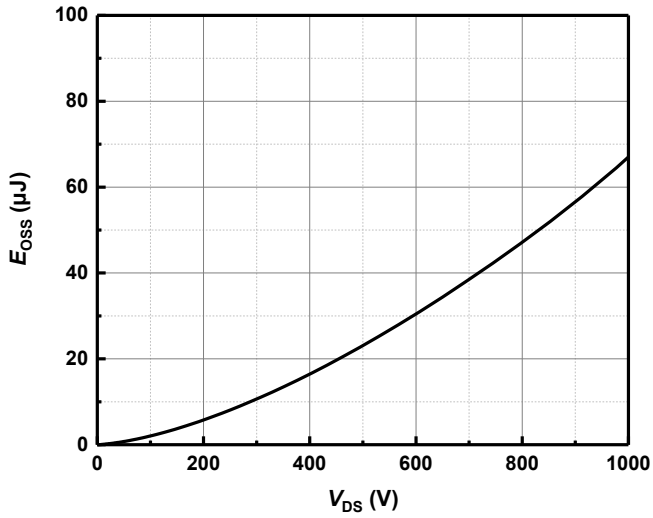


**Figure 11** 3rd Quadrant Characteristics at  $T_j=25^\circ\text{C}$

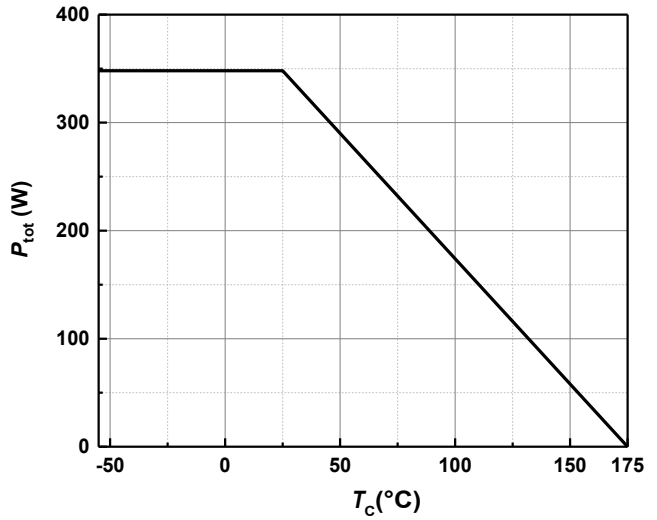


**Figure 12** 3rd Quadrant Characteristics at  $T_j=175^\circ\text{C}$

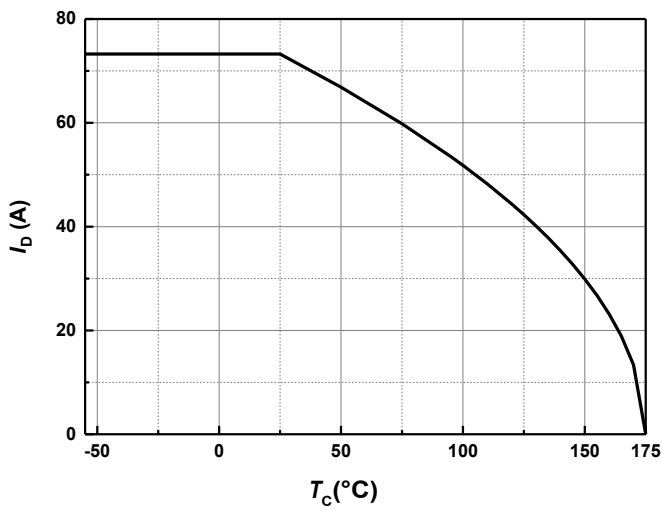
**Typical Performance**



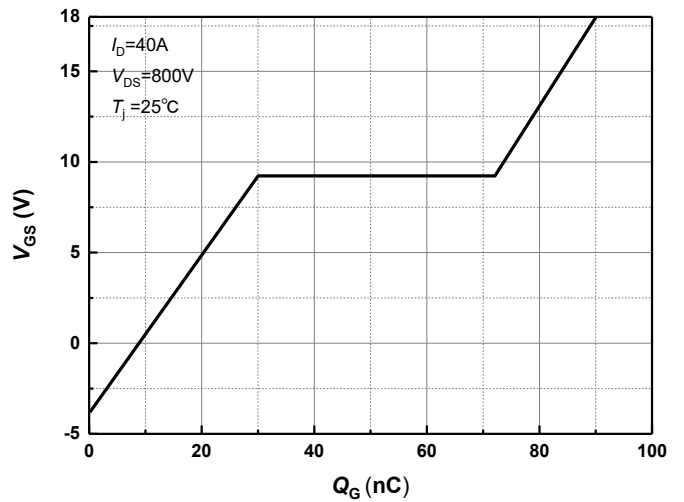
**Figure 13 Output Capacitor stored Energy**



**Figure 14 Maximum Power Dissipation Derating vs. Case Temperature**

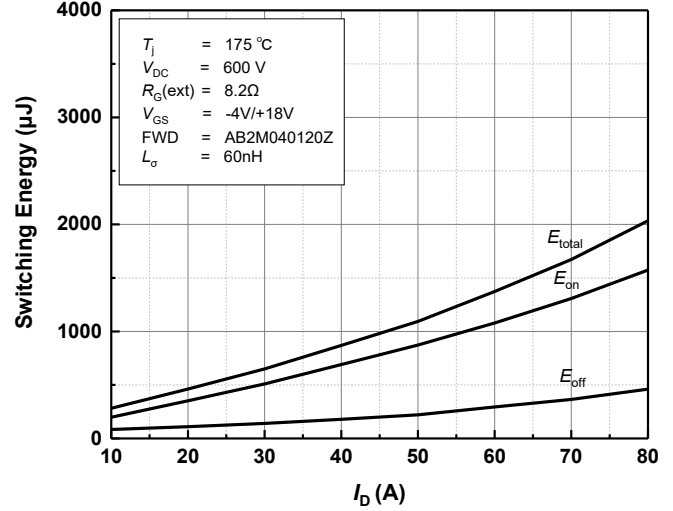
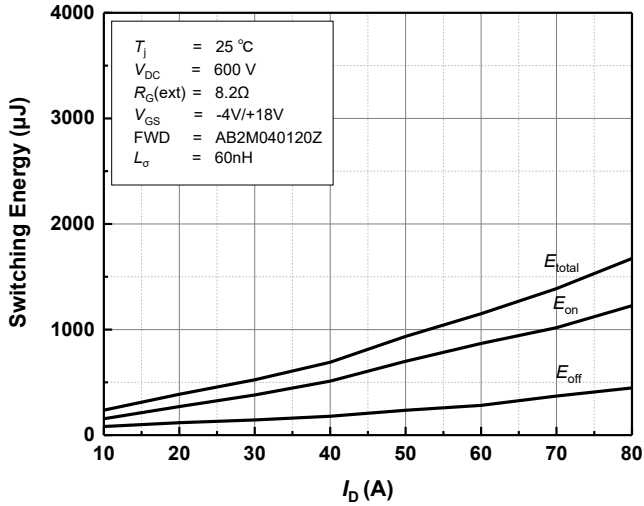


**Figure 15 Continuous Drain Current Derating vs. Case Temperature**



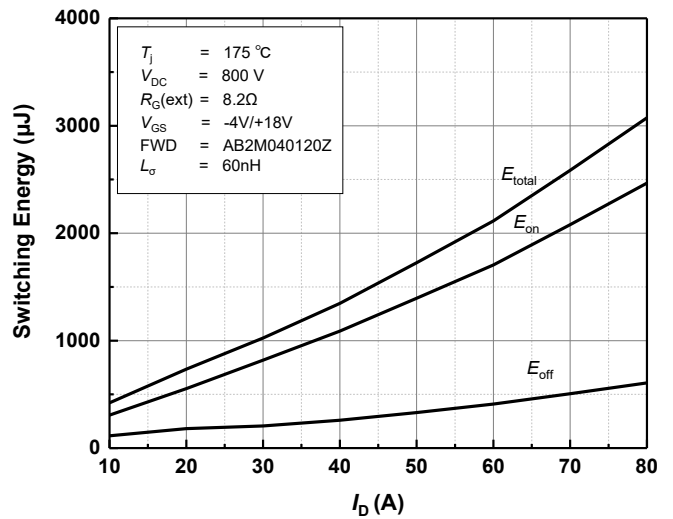
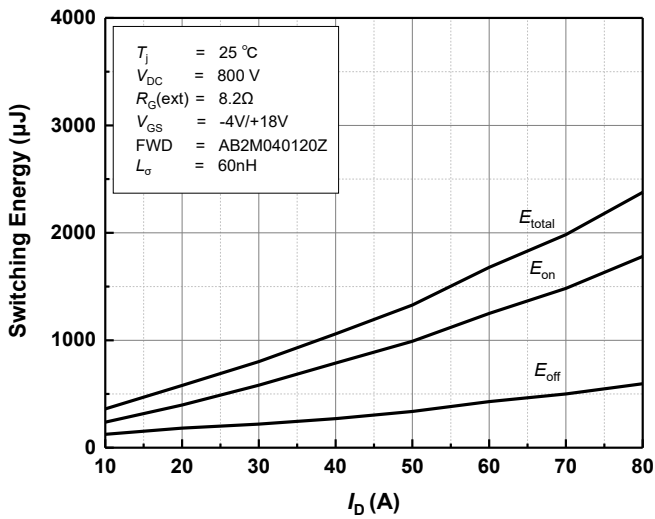
**Figure 16 Gate Charge Characteristics**

**Typical Performance**



**Figure 17 Clamped Inductive Switching Energy vs. Drain Current ( $V_{DC} = 600\text{V}$ ) at  $T_j = 25^\circ\text{C}$**

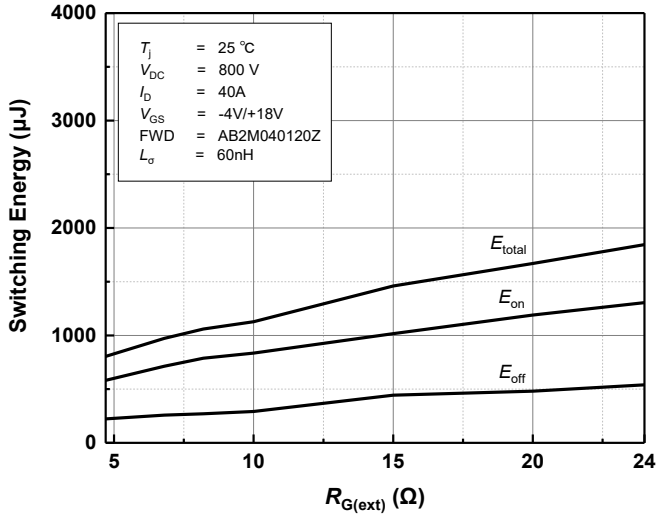
**Figure 18 Clamped Inductive Switching Energy vs. Drain Current ( $V_{DC} = 600\text{V}$ ) at  $T_j = 175^\circ\text{C}$**



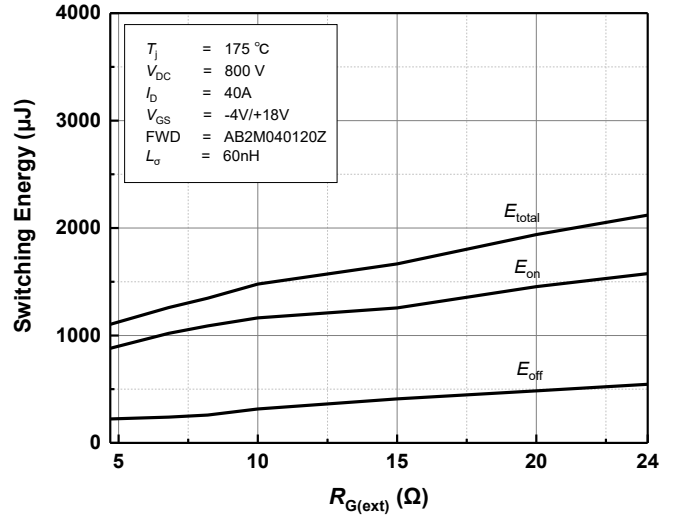
**Figure 19 Clamped Inductive Switching Energy vs. Drain Current ( $V_{DC} = 800\text{V}$ ) at  $T_j = 25^\circ\text{C}$**

**Figure 20 Clamped Inductive Switching Energy vs. Drain Current ( $V_{DC} = 800\text{V}$ ) at  $T_j = 175^\circ\text{C}$**

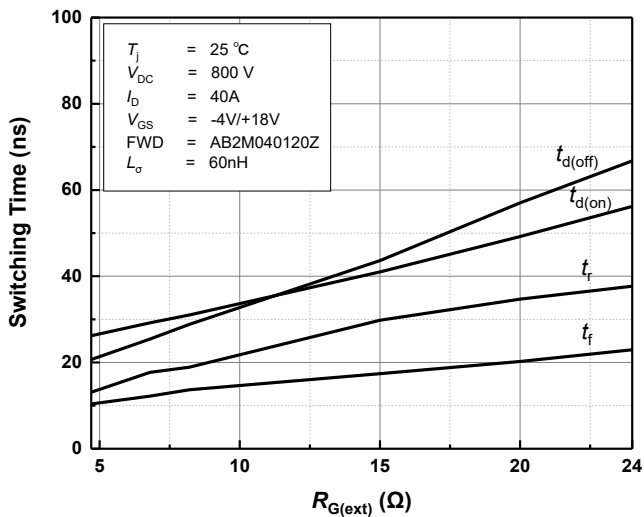
**Typical Performance**



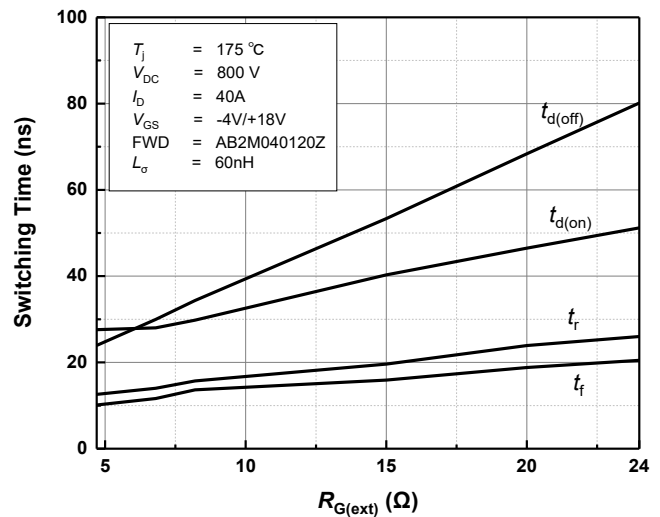
**Figure 21 Clamped Inductive Switching Energy vs. External Gate Resistance at  $T_j=25^\circ\text{C}$**



**Figure 22 Clamped Inductive Switching Energy vs. External Gate Resistance at  $T_j=175^\circ\text{C}$**

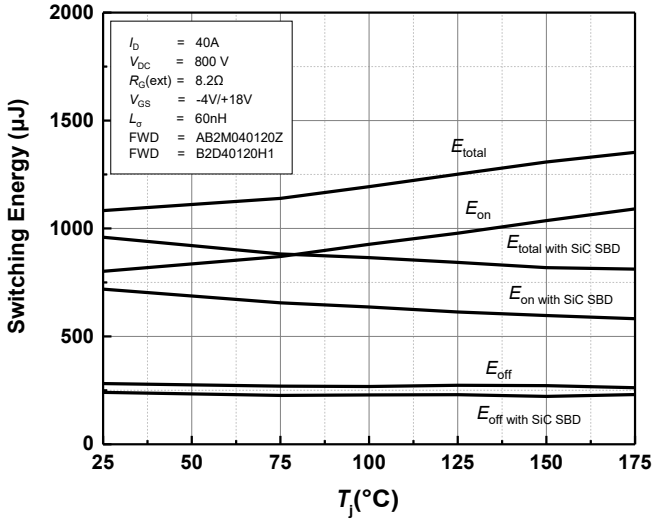


**Figure 23 Clamped Inductive Switching Time vs. External Gate Resistance at  $T_j=25^\circ\text{C}$**

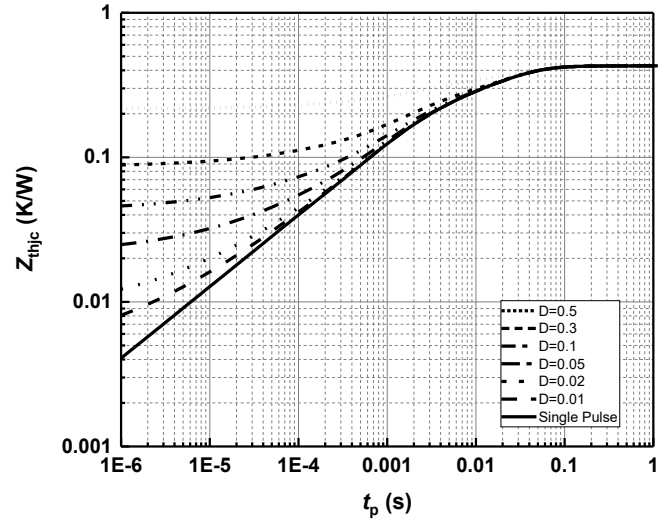


**Figure 24 Clamped Inductive Switching Time vs. External Gate Resistance at  $T_j=175^\circ\text{C}$**

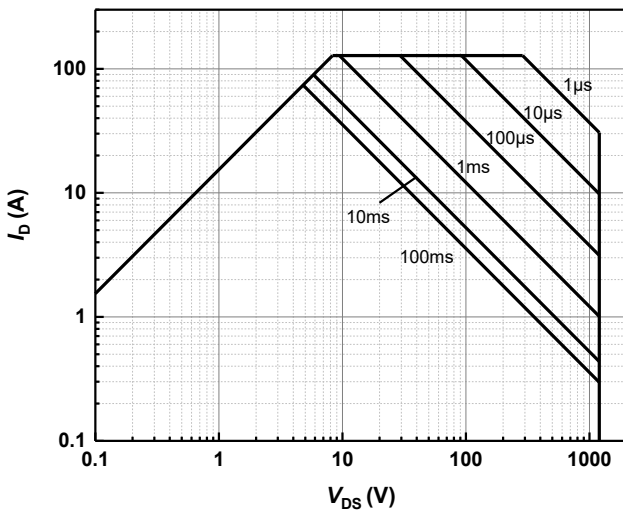
**Typical Performance**



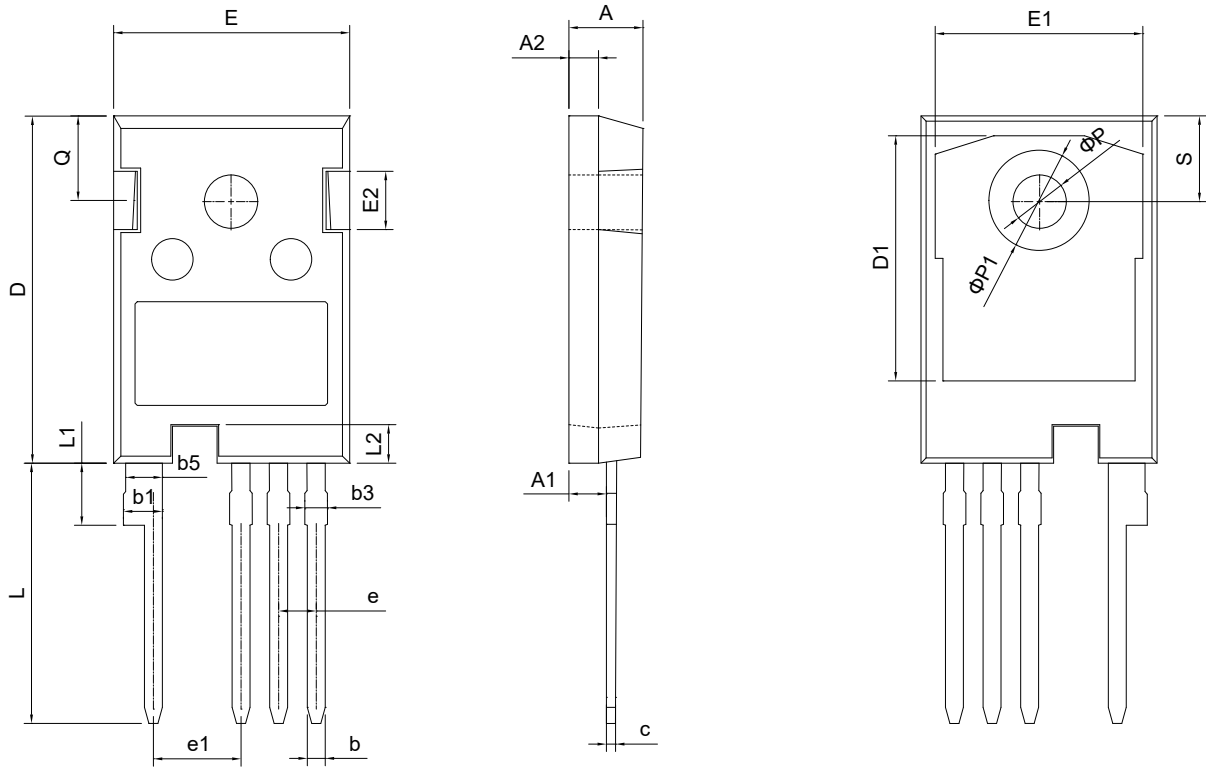
**Figure 25 Clamped Inductive Switching Energy vs. Temperature**



**Figure 26 Transient Thermal Impedance (Junction - Case)**



**Figure 27 Forward Biased Safe Operating Area**

**Package Dimensions**


SYMBOL	mm		
	MIN	NOM	MAX
A	4.80	5.00	5.21
A1	2.21	2.41	2.61
A2	1.80	2.00	2.20
b	1.06	1.21	1.36
b1	2.33	2.63	2.93
b3	1.07	1.30	1.60
b5	2.30	2.53	2.72
c	0.51	0.61	0.75
D	23.30	23.45	23.60
D1	16.25	16.55	17.65
E	15.74	15.94	16.14
E1	13.72	14.02	14.32
E2	3.68	4.40	5.10
e	2.54 BSC		
e1	5.08 BSC		
L	17.27	17.57	17.87
L1	3.97	4.19	4.39
L2	2.35	2.50	2.65
φ p	3.40	3.60	3.80
φ p1	7.19REF		
Q	5.49	5.79	6.09
S	6.00	6.17	6.40

**Revision History**

<b>Document Version</b>	<b>Date of Release</b>	<b>Description of Changes</b>
Rev. 0.0	2024-02-27	Characteristics updated.

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**Shenzhen, China**  
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